Liquid Chemical Japan TC Chapter

Meeting Summary and Minutes

SEMI Japan Standards Winter 2017 Meetings

Friday, Dec 13, 2017, 10:00-12:00

SEMICON Japan 2017, Tokyo Big Sight, Tokyo, Japan

TC Chapter Announcements

Next TC Chapter Meeting

April 23, 2018 Begin 15:00 – End 17:00

SEMI Japan, Tokyo, Japan

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Hiroshi Tomita (Toshiba Memory), Hiroyuki Araki (SCREEN Semiconductor Solutions)
SEMI Staff: Mizue Iwamura

Company	*Last*	*First*	*Company*	*Last*	*First*
Advance Electric Company	Sasao	Kimihito	PMS Division / Spectris Co., Ltd.	Kato	Kazutoshi
Nihon Entegris	Nagafuchi	Takuya	PMS Division / Spectris Co., Ltd.	Takeshita	Mitsuyoshi
Organo	Futatsuki	Takashi	Rion	Kondo	Kaoru
Organo	Sugawara	Hiroshi	SCREEN Semiconductor Solutions	Araki	Hiroyuki
Pall	Mizuno	Takehito	Toshiba Memory Corporation	Tomita	Hiroshi
Pall	Tuzuki	Shuichi	SEMI Japan	Iwamura	Mizue

Table 2 Leadership Changes

WG/TF/SC/TC Name	*Previous Leader*	*New Leader*
None.		

Table 3 Committee Structure Changes

Previous WG/TF/SC Name	*New WG/TF/SC Name or Status Change*
None.	

Table 4 Ballot Results

Document #	*Document Title*	*Committee Action*
#6196	Reapproval of SEMI C77-0912, Test Method for Determining the Counting Efficiency of Liquid-Borne Particle Counters for Which the Minimum Detectable Particle Size is Between 30 nm and 100 nm	Passed as balloted
#6197	Reapproval of SEMI F110-0712, Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters	Passed, as balloted

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

#	Type	SC/TF/WG	Details
None.			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	Type	SC/TF/WG	Details
TBD	SNARF	Liquid-borne Particle Counter Task Force	Line Item Revision of SEMI C77-0912, Test Method for Determining the Counting Efficiency of Liquid-Borne Particle Counters for Which the Minimum Detectable Particle Size is Between 30 nm and 100 nm

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:
http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF

Table 7 Authorized Ballots

#	When	TF	Details
TBD	Cycle 2, 2108	Liquid-borne Particle Counter Task Force	Line Item Revision of SEMI C77-0912, Test Method for Determining the Counting Efficiency of Liquid-Borne Particle Counters for Which the Minimum Detectable Particle Size is Between 30 nm and 100 nm

Table 8 SNARF(s) Granted a One-Year Extension

#	TF	Title	Expiration Date
None.			

Table 9 SNARF(s) Abolished

#	TF	Title
None.		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	Title
None.	

Table 11 New Action Items

Item #	Assigned to	Details
20171213_01	Hiroyuki Araki (SCREEN Semiconductor Solutions)	To confirm with INE. Feedback will be reported at the committee.
20171213_02	Mizue Iwamura	To send SEMI Regulations and PM to the participants of this meeting.

Table 12 Previous Meeting Action Items

Item #	Assigned to	Details
LC170421-1	SEMI	To send the “Table of Contents and Section Contents” and “Appedix 3” of Procedure Manual to the attendees. Closed
LC170421-2	SEMI	To prepare reapproval SNARF of *SEMI F110-0712, Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters* Closed

Table 12 Previous Meeting Action Items

Item #	*Assigned to*	*Details*
LC170421-3	SEMI	To submit reapproval ballot of *SEMI F110-0712, Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters*, for Cycle 5, 2017. Closed
LC170421-4	SEMI	To prepare reapproval SNARF of *SEMI C77-0912, Test Method for Determining the Counting Efficiency of Liquid-Borne Particle Counters for Which the Minimum Detectable Particle Size is Between 30 nm and 100nm.* Closed
LC170421-5	SEMI	To submit reapproval ballot of *SEMI C77-0912, Test Method for Determining the Counting Efficiency of Liquid-Borne Particle Counters for Which the Minimum Detectable Particle Size is Between 30 nm and 100nm*, for Cycle 7, 2017. Closed

1 Welcome, Reminders, and Introductions

Hiroshi Tomita (Toshiba Memory Corporation) called the meeting to order at 10:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: To approve the minutes of the previous meeting as written.
By / 2nd: Hiroyuki Araki (SCREEN Semiconductor Solutions) / Takehito Mizuno (Pall)
Discussion: None.
Vote: 10 in favor and 0 opposed. Motion passed.

3 Liaison Reports

3.1 *Gases and Liquid Chemical Europe TC Chapter*

Mizue Iwamura reported for the *Liquid Chemical Europe* TC Chapter as attached.

Attachment: 03_01_EU Gases & Liquid Chemicals liaison report

3.2 *Liquid Chemical North America TC Chapter*

Mizue Iwamura reported for the *Liquid Chemical North America* TC Chapter as attached.

Attachment: 03_02_NA Liquid Chemicals Liaison Report Nov 2017_v4

3.3 *SEMI Staff Report*

Mizue Iwamura gave the SEMI staff report. This report included SEMI Global 2018 Calendar of Events, Global Standards Meeting Schedule, 2017 and 2018 Critical Dates for SEMI Standards Ballots, A&R Ballot Review, SEMI Standards Publication, JRSC Organization Chart, SEMI TSUSHIN Information, Global Staff Assignment and Staff Contact Information.

Attachment: 03_03_SEMI Staff Report 20171212b

4 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

4.1 Document # 6196, Reapproval of SEMI C77-0912: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm

The ballot passed TC Chapter review as balloted. See attachment for ballot adjudication.

Attachment: 04_01_6196_BallotReport

4.2 Document # 6197, Reapproval of SEMI F110-0712: TEST METHOD FOR MONO-DISPERSED POLYSTYRENE LATEX (PSL) CHALLENGE OF LIQUID FILTERS

The ballot passed TC Chapter review as balloted. See attachment for ballot adjudication.

Attachment: 04_02_6197_BallotReport

5 Subcommittee and Task Force Reports

5.1 Diaphragm Valve Task Force

Kimihito Sasao (Advance Electric Company) reported that there was no issue currently working on.

5.2 *Welding Fitting Task Force*

Kimihito Sasao (Advance Electric Company) reported that there was no issue currently working on.

5.3 *Liquid Filter Task Force*

Takehito Mizuno (Pall) addressed the committee on Editorial Change to SEMI F110-0712: TEST METHOD FOR MONO-DISPERSED POLYSTYRENE LATEX (PSL) CHALLENGE OF LIQUID FILTERS.

Attachment: 05_03_Report_for_Editorial Change_F110_0712

5.4 *Liquid-borne Particle Counter Task Force*

Kaoru Kondo (Rion) reported that he will submit a SNARF for Line Item Revision to SEMI C77-0912: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm in New Business.

5.5 *Ultrapure Liquid Evaluation Study Group*

Kaoru Kondo (Rion) reported that there was no issue currently working on.

6 Old Business

6.1 SNARF Project Period Check

Mizue Iwamura (SEMI Japan) addressed that there is no SNARF that exceed the project period.

6.2 5 Year Review Check

Mizue Iwamura (SEMI Japan) addressed that there is no SNARF that exceed the project period.

6.3 Asking for cooperation by Interfacial Nono Electrochemistry for solution to the issues concerned to analyzing metals of organic solvent, including IPA

Hiroyuki Araki (SCREEN Semiconductor Solutions) addressed the committee on this topic.

Action Item: Hiroyuki Araki (SCREEN Semiconductor Solutions) will confirm with this issues with INE. Feedback will be reported at the committee.

7 New Business

7.1 SNARF for Line Item Revision to SEMI C77-0912: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm

Kaoru Kondo (Rion) addressed the committee on this topic. The following action was taken.

Motion:	Approve a SNARF for Line Item Revision to SEMI C77-0912: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm
By / 2nd:	Kaoru Kondo (Rion) / Kazutoshi Kato (Spectris)
Discussion:	None.
Vote:	10 in favor and 0 opposed. Motion passed.

Attachment: 07_01_SNARF_c77_201712_r3_Final

7.2 Ballot submission of #TBD: for SEMI C77-0912, TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm to Cycle 2, 2018.

Kaoru Kondo (Rion) addressed the committee on this topic. The following action was taken.

Motion:	To approve a ballot submission of #TBD: for SEMI C77-0912, TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm to Cycle 2, 2018.
By / 2nd:	Kaoru Kondo (Rion) / Kazutoshi Kato (Spectris)
Discussion:	None.
Vote:	10 in favor and 0 opposed. Motion passed.

8 Next Meeting and Adjournment

The next meeting is scheduled for Tuesday, April 23 15:00-17:00 at Japan Standards Spring.

See http://www.semi.org/standards-events for the current list of events.

Adjournment: 12:00

Respectfully submitted by:

Mizue Iwamura

Coordinator

SEMI Japan

Phone: +81-3-3222-5760

Email: miwamura@semi.org

Minutes tentatively approved by:

Hiroshi Tomita (Toshiba Memory), Co-chairs	February 9, 2018
Hiroyuki Araki (SCREEN Semiconductor Solutions), Co-chairs	February 9, 2018

Table 13 Index of Available Attachments[#1]

Title	*Title*
01_02_Required_Elements_Reg_20150327_E+J	04_01_6196_BallotReport
03_01_EU Gases & Liquid Chemicals liaison report	04_02_6197_BallotReport
03_02_NA Liquid Chemicals Liaison Report Nov 2017_v4	05_03_Report_for_Editorial Change_F110_0712
03_03_SEMI Staff Report 20171212b	07_01_SNARF_c77_201712_r3_Final

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.